

Federal Agency on Technical Regulating and Metrology  
(Rostekhnregulirovanie)

**CENTER FOR SURFACE AND VACUUM RESEARCH**

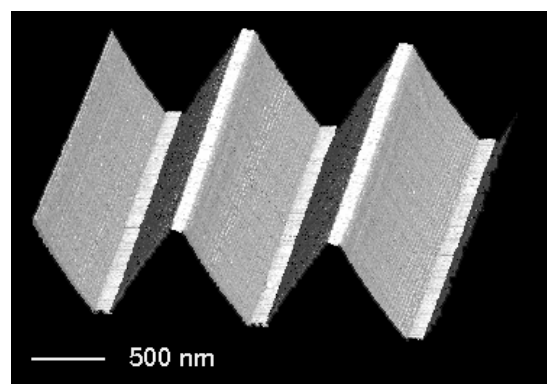
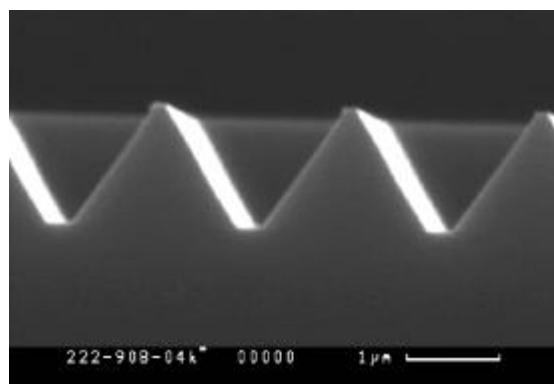
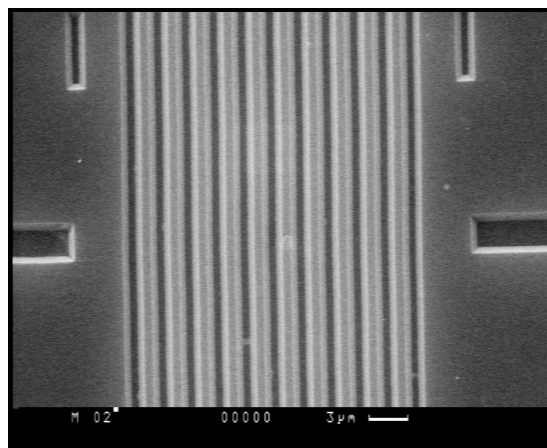
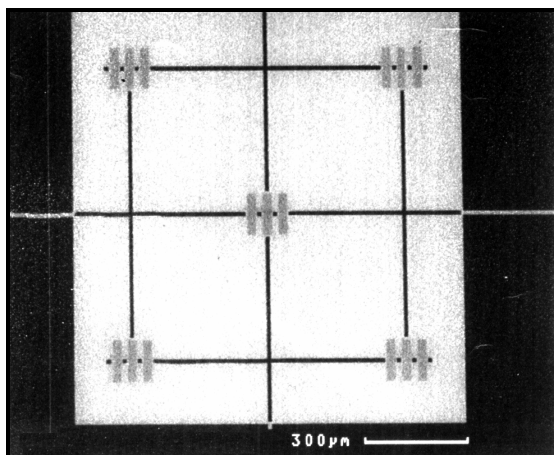
Russian Academy of Sciences  
**GENERAL PHYSICS INSTITUTE**

**Gauge of width and period, special GWPS-2.0Si**

3 dimension stepping reference standard for calibration of linear size measure system in microelectronic and nanotechnology:

**SEM calibration (5 minutes):** magnification, electron probe diameter.  
**AFM calibration (5 minutes):** X-, Y-, Z-scale factors, cantilever tip radius, Scanning linearity and orthogonality.

|                            |               |
|----------------------------|---------------|
| Nominal dimension of step  | 2000 nm       |
| Linewidth                  | 30 ÷ 1500 nm  |
| Depth (height) of relief   | 100 ÷ 1500 nm |
| Accuracy of certification: |               |
| Step                       | ±1 nm         |
| Linewidth                  | ±1 nm         |
| Depth (height) of relief   | ±1 %          |



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